product data

Find Sync Problems Faster and Easier

- Wander measurements on transmission rates from 4 kHz to 52 Mbits/s
- Stability check of any frequency reference clock signal to 50 Hz to 65 MHz
- NEW 1-pps / 125 MHz option for sync testing in packet networks
- MTIE and TDEV masks
- Portable 2.048/1.544 MHz clock generator
- Easy-to-use e.g. auto-calibration of internal Rubidium
- - 48V DC supply and Ethernet interface

Quick Guide to the WM-11

Model:	WM-11
SDH/PDH/SONET Frequencies	
2048 kHz / kbit/s	Х
4 / 8 kHz	Х
64 kbit/s	Х
34 / 45 / 52 Mbit/s	Х
1.544 MHz / Mbit/s	Х
Video Frequencies	
27 MHz	Х
15.750 / 15.625 kHz	Х
Reference Frequencies	
10 MHz / 5 MHz	Х
1 pps and 125 MHz	option 32
Any clock frequency:	
50 Hz65535 Hz in 1 Hz steps	Х
1 kHz65535 kHz in 1 kHz steps	Х
Graphical Display	Х
Rubidium Reference	Х
Ethernet Interface	Х
2.048 MHz Clock Output	Х
1.544 MHz Clock Output	Х
-48V DC Supply	Х

Wandermeter for SDH, PDH, SONET and SyncE (new) synchronization testing

WM-11



Incorrect synchronization in digital communication networks can cause severe transmission problems. Voice calls (fixed or cellular) will be lost, fax machines will misprint, and data will be lost or frequently re-transmitted. In any case, network performance is degraded, the operators' service costs are increased and revenues are down.

The main cause for synchronization problems in transport networks is wander of the synchronization clock. Quality control of the synchronization clock requires monitoring of wander over a longer period (hours or days) using an ultra-stable clock as reference.

Measurement of wander has earlier involved bulky, complex and very expensive instrumentation. To be able to measure and view the wander parameters MTIE and TDEV, external Rubidium standards and/or external computers were often needed.

Pendulum Instruments offers the WM-11, a multi-application synchronization testing tool for a multitude of data rates in SDH, PDH, SONET, Video and frequency reference distribution networks covering frequencies from 50 Hz to 65 MHz.

The *new* extended frequency range option, and the optional SyncE-tap enables wander measurements in packet networks (SyncE) via additional 1-pps and 125 MHz reference measurements.

Applications

WM-11 can be used both by the transport network owners and all users of the network, e.g. GSM network operators and radio link services. Applications are several:

- As an accurate certification tool, to document conformance to standards (ANSI T1.10x, ITU G811-813, ETS 300 462) for telephone network operators, network leasers, and buyers/sellers of synchronization services.

- As a preventive (diagnostic) maintenance tool in transport nodes using SONET, SDH or PDH.

- As a quick trouble-shooting tool in SONET, SDH or PDH networks when a node is suspected not to operate correctly.

- As a design tool for manufacturers of equipment for SONET, SDH and PDH and network elements, PBX'es, GSM access equipment, Radio links etc.

- As a sync quality measurement tool for packet based backhaul networks using SyncE or PTP

- As a remote monitoring station with remote control and network wander data retrieval over Internet.

pendulum Incorporating XL Microwave

Measures to Standard

The WM-11 Wandermeter is designed to measure wander according to ITU- and ANSI-standards of various signals in SONET, SDH- or PDH-network nodes, with graphical presentation of TIE, MTIE and TDEV and comparison to standard masks e.g. PRC, SSU, SEC. It is possible to create user-defined masks, for new or changed standards, for easy recall of the operator during measurements.

WM-11 can measure both "absolute" and "relative" wander. In the first case the measured signal (clock or data) is compared to the ultimate stability of the internal Rubidium "atomic" clock or an external 10 MHz reference. In the second case, the relative wander between two signals, e.g. in- and outgoing E1-signal from a network element, is measured. This makes it possible to verify wander tolerance and the amount of "extra wander" created by the device under test.

Complete Unit

The instrument is compact, lightweight and fully self-contained with a build-in Rubidium reference clock and a graphical display. There is no need to carry around an external frequency standard or a separate PC to make and view the measurement. A PC-cable and 120Ω -to- 75Ω transformers are included as standard, to enable measurement on any kind of cable system, whether 75Ω unbalanced or 120Ω balanced.

WM-11 offers an Ethernet interface, a 1.544/ 2.048 MHz clock and a –48V DC voltage supply as standard.

Easy to Operate and Calibrate

The unit is very easy to use and can even be operated by unskilled personnel. For standard measurements only a few keystrokes are required. Once the measurement is started, the WM-11 can be left unattended for automatic measurements. It stops automatically after set measuring time and can even delay its measurement start when required.

A fully automatic signal check informs the user whether he/she has connected the right signal from the rack.

On-line context-sensitive help is available, making the operator's manual obsolete.

The calibration and adjustment of the internal Rubidium clock is fully automatic and very easy to use. Just connect a known reference signal from a Cesium or a GPS-controlled Rubidium clock, enter the calibration mode of WM-11 and leave the unit over-night. Next morning, the WM-11 is perfectly adjusted, without any manual trimming involved.

The WM-11 is also easy to carry and transport, and includes e.g. side handles and a flight-proof transport case (extra accessory).

SyncE and PTP sync measurements

The extended frequency range option (option 32) enables measurements on the basic 125 MHz clock in SyncE networks. The network clock is extracted from the network traffic using the optional SyncE-tap (option 31). The Sync-E tap can be inserted in the normal traffic flow, without affecting the network payload data.

In PTP synchronized networks, the option 32 enables precise wander measurements on 1-pps timing signals.

Working Principle

The Pendulum Wandermeter contains a Rubidium Reference, and a special in-house developed Time Interval Error (TIE) measuring circuitry that phase compares the connected signal with the Rubidium reference. The WM-11 communicate its results to the user via a graphical display, and via an RS232-port or an Ethernet-port. See figure 1.

WM-11 operates in two different modes; local and remote.

Local Mode Operation

During the measurement, the TIE-curve on the display is continuously updated. This mode is intended for automated diagnostics and/or fault-finding measurement "on-site", with direct visual feedback at any time. The sampling rate is approx. 1 Sa/s. The Wandermeter calculates and presents the MTIE or TDEV curves, and compares them to stored masks.

Remote (PC-controlled) Operation

The WM-11 Wandermeter can be operated via RS232 or Ethernet, running the WanderViewTM PC-SW. See figure 2. In this mode the Wandermeter acts a sampling front-end and transfers the TIE-values to the PC. Once you have installed the WM-11 at one network node location to perform measurements, you do not need to travel back to get the result. You can read the data, and start new measurements from anywhere using the Internet.

Sample speed is >30 TIE-values/s, and the storage is only limited by the PC. The PC-SW calculates and presents MTIE and TDEV curves, and compares to the defined masks. This mode is intended for verification of conformance to ETSI- or ANSI- standards. Multiple graphs can be displayed on-screen, and multiple masks can be applied.

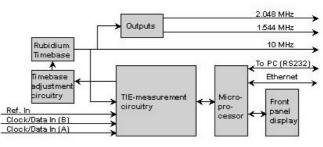


Figure 1: Block diagram of WM-11

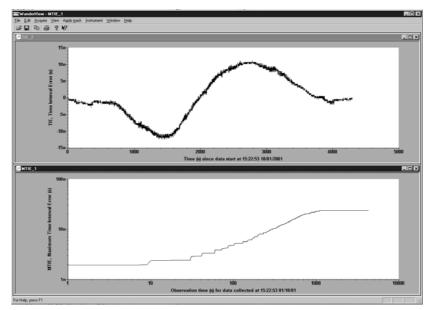


Figure 2: WanderWiew screen, showing a TIE-curve (top) and a MTIE curve (bottom).

WM-11 Specifications

Note: Specifications apply after 30 minutes of warm-up time

Operation Modes

Local: The WM-11 Wandermeter operates stand-alone and measures the wander of a connected clock or data signal. Alternatively the differential phase (Time Interval) between two connected clocks or data signals is measured. During the measurement, the TIE curve is continuously updated on the display.

Remote: The WM-11 Wandermeter is controlled from a PC running the WanderView PC-software and measures the wander of a connected clock or data signal. During the measurement, the WM-11 Wandermeter acts as a sampling front-end. This mode has no limitation in sampling rate (<30 Sa/s) and number of stored samples. TIE is presented graphically on screen, in real-time, and current MTIE and TIE values are continuously displayed numerically.

Presentation Modes

TIE: Time Interval Error is displayed and continuously updated in Local Mode operation.

MTIE: MTIE is calculated from the measured and stored TIE-values and displayed after completed measurement in Local Mode operation. TDEV: TDEV is calculated from the measured and stored TIE-values and displayed after complete measurements in Local Mode operation

Test Modes (MTIE and TDEV Masks)

The internal Rubidium clock is used as reference in all modes except "Differential". Mask applies for MTIE and TDEV graphs.

Draft:	No mask
PRC/SSU/SEC:	Masks for G811/G812/G813-clocks (ETS 300 462-3)
ANSI-standard:	DS1 and OC-N masks
Video:	NTSC and PAL masks
User-defined:	Any
Differential:	Relative Wander (TIE, MTIE and TDEV) between two clocks or data signals.

Signal Types – predefined

1 pps (option 32) 4 kHz 8 kHz 64 Khit/s 1 544 MHz 1 544 Mbit/s 2.048 MHz 2.048 Mbit/s 5 MHz 10 MHz 25 MHz (option 32) 27 MHz 125 MHz (option 32) 34 Mbit/s 45 Mbit/s 52 Mbit/s 15 750 kHz 15.625 kHz

Clock Signal Types – user settable

50 Hz to 65535 Hz in 1 Hz steps (from 1 Hz to 65535 Hz with option 32) 1 kHz to 65535 kHz in 1 kHz steps

Note: The signal under test must be a symmetrical clock-type signal

Input Signal Characteristics

Frequency:	4 kHz, 8 kHz, 64 kbit/s, 1.544 MHz, 1.544 Mbit/s, 2.048 MHz, 2.048 Mbit/s, 10 MHz, 27 MHz, 34 Mbit/s, 45 Mbit/s, 52 Mbit/s, 15.750 KHz, 15.625 KHz (PAL)
Amplitude:	Inside -5V+5V
Signal Type:	Symmetrical pulse (Clock signal) Unsymmetrical repetitive pulse (Clock signal)
	HDB3-coded data (Data signal)
	AMI B8ZS, B3ZS (Data signal)

Time Interval Error (TIE)

Reference Clock:	Built-in Rubidium clock or an external 10 MHz clock signal connected to Ext. Reference input
Measure Time:	30 min, 2h, 4h, 24h or continuously (local mode)
Local Mode Update Rate	
30 min, 2h, 4h:	approx. 1 Sa/s
24h:	approx. 0.2 Sa/s (1Sa/6s)
Continuously:	16000/time Sa/s; max. approx. 1 Sa/s. Data compression after approx. 4h
Remote Mode Update Ra Any Measure Time:	te: up to 30 Sa/s
	*
Internal data stor	
Size:	16000 stored TIE values
Туре:	Non-volatile storage
Measuring Time	
Time:	Short (30 min, 2h, 4h), long (24h) and continuous
Start/Stop:	via START/STOP key.
Warm-up Time:	Selectable delay before measurement starts, to allow the instrument to warm-up properly; 0, 30 min, 4h or 24h.
Signal Check	
measures and Displays th	he Following Parameters: Signal type (Clock, Data or Unknown)
	Frequency (for clock signals)
	Pulse width (for data signals)
	Voltage peak-peak (min. 120 mVp-p)
Self Test	
Power-up:	Test of critical digital functions
On Demand (user opt.):	Test of the most digital funciton
Info	č
	elp function gives guidance for all manual settings.
SAVE / RECALL	
No. of Instrument Set-up	s: 5
No. of Screen Images:	3 (TIE, MTIE or TDEV)
Stored TIE-value Array:	16k values (1 set)
Stored TIE-value Array: Write Protection:	16k values (1 set) Saved set-up, screen image or TIE-value array can be
Stored TIE-value Array: Write Protection:	16k values (1 set) Saved set-up, screen image or TIE-value array can be
Stored TIE-value Array: Write Protection: Graph Display	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing.
Stored TIE-value Array: Write Protection: Graph Display Display Modes:	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test
Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale:	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale)
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Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11:	 16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode
Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11: Clock / Data inpu	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode t A and B
Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11: Clock / Data inpu Connector:	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode t A and B BNC
Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11: Clock / Data inpu Connector: Coupling:	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode t A and B BNC DC Coupled
Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11: Clock / Data inpu Connector: Coupling: Voltage Range:	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode t A and B BNC DC Coupled ± 5.00V
Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11: Clock / Data inpu Connector: Coupling:	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode t A and B BNC DC Coupled ± 5.00V 60 mVpp
Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11: Clock / Data inpu Connector: Coupling: Voltage Range: Sensitivity: Impedance:	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode t A and B BNC DC Coupled ± 5.00V 60 mVpp 75Ω, VSWR <2:1
Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11: Clock / Data inpu Connector: Coupling: Voltage Range: Sensitivity: Impedance: Maximum Input Voltage	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode b NC DC Coupled ± 5.00V 60 mVpp 75Ω, VSWR <2:1
Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11: Clock / Data inpu Connector: Coupling: Voltage Range: Sensitivity: Impedance: Maximum Input Voltage Trigger Level:	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode t A and B BNC DC Coupled ± 5.00V 60 mVpp 75Ω, VSWR <2:1
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Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11: Clock / Data inpu Connector: Coupling: Voltage Range: Sensitivity: Impedance: Maximum Input Voltage Trigger Level: Range: External Reference Connector:	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode t A and B BNC DC Coupled \pm 5.00V 60 mVpp 75Ω, VSWR <2:1
Stored TIE-value Array: Write Protection: Graph Display Display Modes: Vertical Scale: Horizontal Scale: No of Divisions: Masks WM-11: Clock / Data inpu Connector: Coupling: Voltage Range: Sensitivity: Impedance: Maximum Input Voltage Trigger Level: Range: External Reference Connector: Input Frequency:	16k values (1 set) Saved set-up, screen image or TIE-value array can be protected against accidental over-writing. TIE, MTIE or TDEV Displayed TIE, MTIE or TDEV value in ns or ms. AUTO scaled Real-time axis (TIE) or "τ"- axis (MTIE/TDEV). AUTO scaled (continuous measurement and differential test mode) or fixed scaled (2h/24h full scale) 8x10 (vert. x horiz.) MTIE and TDEV masks according to selected test mode t A and B BNC DC Coupled \pm 5.00V 60 mVpp 75Ω, VSWR <2:1
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WM-11 Specifications

Reference Frequ	iency Output	Resolution:	240x240 pixels	
Connector:	BNC	Backlight:	Cold Cathode Fluorescent (CCFL) tube.	
Ref. Frequency:	10 MHz square-wave		Brightness approx. 50 cd/m ²	
Frequency Stability:	See Internal Timebase Stability spec.	Contrast Ratio:	User adjustable, max. 1:15 (typical at 20°C)	
Output Levels:	Fixed TTL: low <0.4V, high >1.8V into 50Ω	Environmental Data		
1.544 / 2.048 MH	z Clock Output	Temperature:		
Connector:	BNC	Operating:	0°C to 50°C	
Ref. Frequency:	1.544/2.048 MHz square-wave	Storage:	-20°C to 70°C	
Frequency Stability:	See Internal Timebase Stability spec.	Humidity:		
Jitter:	<0.01 UI	Operating:	20°C to 30°C, 90% RH non-condensing 30°C to 50°C, 70% RH non-condensing	
Wander:	$MTIE < 15 \text{ ns} + \tau \text{ x (freq.offset)}^{-1}$	Storago	95% RH	
Output Level:	Acc. to G703:10; $\pm 1.2V \pm 10\%$ in 75 Ω	Storage: Altitude:	95% Kn	
-		Operating:	3 000m (10 000 ft)	
RS232 Data in/o	•	Storage:	12 000m (40 000 ft)	
Connector:	9-pin male D-Sub connector	Safety:	EN 61010-1:1997, CAT II, Pollution degree 2, CE	
Baud Rate:	4800 to 19200 bps	EMC:	EN 55022B, EN 61000-6-2, CE	
Data Format:	8 databits, 1 stopbit, no parity		ER 55622B, ER 61666 6 2, CE	
Ethernet		Power Supply	100 / 240 X/ 100/	
Communication Port:	RJ45	Line Voltage:	100 to 240 Vrms ±10% 47 Hz to 63 Hz, <60 W	
Protocol:	10Base-T	-48V DC Voltage:	38V to 60V DC, <60W	
Configuration Port:	Dsub9, RS232	5		
WanderView SW	1	Mechanical Data		
Operating System:	Windows 2000/XP/Vista	WxHxD: Weight:	342x177x305 mm Net 5 kg (11 lb)	
Data Transfer from WM		weight:	Shipping 7 kg (15 lb).	
	TIE-values (real-time or stored values) Stored graphs	SyncE-tap (Optio		
	Instrument id	WxHxD:	113x30x190 mm	
	Setup information	Weight:	Net 0.5 kg (1.1 lb)	
Calculate Functions:	MTIE, RTIE, MRTIE, TDEV, ADEV, MADEV, FDEV	Versions Option 31/01:	Network Link: 1000B-LX 1310nm, Singlemode, LC	
Instrument Control Fur		Versions Option 31/02:	Network Link: 1000B-SX 850nm, Multimode, LC	
	Local or Remote mode Auto-adjust of Rubidium osc.	Ordering Informa	ation	
	Instrument setup	WM-11 Wandermeter:	Wandermeter 50 Hz to 65 MHz	
Self Test:	Start/Stop TIE measurement	Included with Instrumen		
	Install new/updated Signal Types		Two 120Ω -to- 75Ω transformers (BNC mounted)	
	Install new/updated Masks		PC connection cable	
	<i>M-11:</i> Unlimited user defined MTIE+TDEV mask		Operators Manual on CD	
File Functions:	Document printout, File save/retrieve		Certificate of calibration	
Window Types:	Graph windows of TIE and calculated parameters (un- limited)	Built-in option: Option 32:	Extended Frequency range 1 Hz to 125 MHz	
	Measurement set-up window	option 52.	Extended Frequency range Fills to 125 Mills	
	Event log window (logs e.g. transmission interrupts)	Optional Accessories:		
Calibration		Option 27W:	Heavy Duty Hard Transport Case	
Principle:	Closed Case Calibration with automatic adjustment of	Option 31/01:	SyncE-tap for 1310 nm, Single mode, LC	
	the Rubidium timebase.	Option 31/01:	SyncE-tap for 850nm, Multi-mode, LC	
Calibration Reference:	Cs-oscillator or GPS-controlled Rubidium	Option 31/02: Option 31/09:	19" rackmount for option 31 (1, 2 or 3 can be mounted	
Calibration Ref. Freque	<i>ency:</i> 100 kHz, 1, 1.544, 2.048, 5 or 10 MHz	Option 51/07.	17 Tackmount for option 51 (1, 2 or 5 can be mounted	
Calibration Uncertainty	$\sim 2 \times 10^{-12}$ + Cal. Ref. Freq. Uncertainty			

Internal Time Base Stability

Stability Versus			
Temperature:	20° to 26° 0° to 50°	$<2x10^{-11}$ $<3x10^{-10}$	
Aging Rate per:	24h Month	$<2x10^{-12}$ (typ.) $<5x10^{-11}$	
Short Term Stability per:	1s 10s	$<3x10^{-11}$ $<1x10^{-11}$	
Warm-up Stability:	10 min	$<4x10^{-10}$	
Factory Adjustment Uncertainty (+23°C):	<10 MHz ±0.0	<10 MHz ±0.0005 Hz	

Display

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Super Twisted Liquid Crystal 84 x 84 mm, 4.7" diagonal

Specifications subject to change without notice

4031 600 11101 rev. 10 March 2010

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- Experts in time & frequency calibration, measurement and analysis

Pendulum Instruments is a company of the Orolia Group

